

February 2008

FDMC4435BZ

P-Channel Power Trench[®] MOSFET -30V, -18A, 20.0m Ω

Features

- Max $r_{DS(on)} = 20.0 \text{m}\Omega$ at $V_{GS} = -10 \text{V}$, $I_D = -8.5 \text{A}$
- Max $r_{DS(on)}$ = 37.0m Ω at V_{GS} = -4.5V, I_D = -6.3A
- Extended V_{GSS} range (-25V) for battery applications
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- HBM ESD protection level >7kV typical (Note 4)
- 100% UIL Tested
- Termination is Lead-free and RoHS Compliant

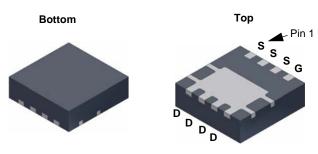
General Description

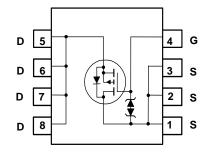
This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This devie is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Applications

- High side in DC DC Buck Converters
- Notebook battery power management
- Load switch in Notebook







Power 33

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			-30	V
V_{GS}	Gate to Source Voltage			±25	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		-18	
I _D	-Continuous (Silicon limited)	T _C = 25°C		-31	
	-Continuous	T _A = 25°C	(Note 1a)	-8.5	A
	-Pulsed			-50	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	24	mJ
D	Power Dissipation	T _C = 25°C		31	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.3	- VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC4435BZ	FDMC4435BZ	Power 33	13"	12mm	3000 units

Units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter

Off Char	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} = -24V, V_{GS} = 0V, T_{J} = 125°C			-1 -100	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±10	μА

Test Conditions

Min

Тур

Max

On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1.0	-1.9	-3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		-5.3		mV/°C
		$V_{GS} = -10V, I_D = -8.5A$		14.6	20.0	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -4.5V, I_D = -6.3A$		23.1	37.0	mΩ
	$V_{GS} = -10V, I_D = -8.5A, T_J = 125$ °C		20.7	28.0		
9 _{FS}	Forward Transconductance	$V_{DD} = -5V, I_{D} = -8.5A$		24		S

Dynamic Characteristics

C _{iss}	Input Capacitance	45)/)/ 0)/	1540	2045	pF
C _{oss}	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$ f = 1MHz	295	395	pF
C _{rss}	Reverse Transfer Capacitance	1 – 1101112	260	385	pF
R_q	Gate Resistance	f = 1MHz	5.1		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		$V_{DD} = -15V, I_{D} = -8.5A,$ $V_{GS} = -10V, R_{GEN} = 6\Omega$		10	20	ns
t _r	Rise Time	$V_{DD} = -15V, I_D = -8.$			6	12	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = -10V, K _{GEN} =	= 075		34	55	ns
t _f	Fall Time				20	36	ns
Q_g	Total Gate Charge	V _{GS} =0V to -10V			33	46	nC
Q_g	Total Gate Charge	$V_{GS} = 0V \text{ to } -4.5V$	V _{DD} = -15V,		17	24	nC
Q_{gs}	Gate to Source Charge		$I_{D} = -8.5A$		5		nC
Q_{ad}	Gate to Drain "Miller" Charge				9		nC

Drain-Source Diode Characteristics

V Source to Drain Diode, Forward	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -8.5A$ (Note 2))	0.92	1.5	\/
V _{SD}	Source to Drain blode Forward voltage	$V_{GS} = 0V, I_S = -1.9A$ (Note 2))	0.75	1.2	V
t _{rr}	Reverse Recovery Time	I _F = -8.5A, di/dt = 100A/μs		22		ns
Q _{rr}	Reverse Recovery Charge	$_{\text{IF}} = -6.5A$, $_{\text{U/U}} = 100A/\mu s$		11		nC

^{1:} R_{8JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



 b. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2: Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. Starting T_J = 25°C, L = 1mH, I_{AS} = -7A, V_{DD} = -27V, V_{GS} = -10V.
- 4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics $T_J = 25$ °C unless otherwise noted

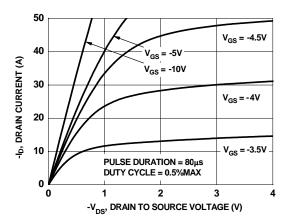


Figure 1. On-Region Characteristics

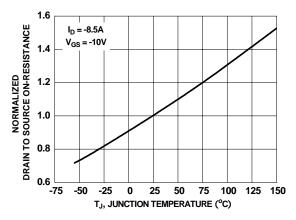


Figure 3. Normalized On-Resistance vs Junction Temperature

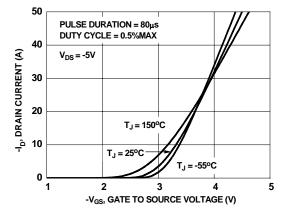


Figure 5. Transfer Characteristics

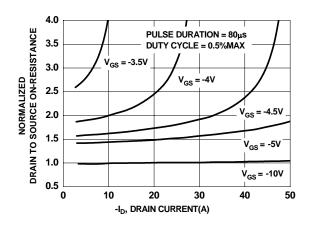


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

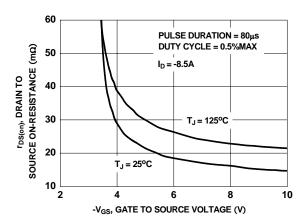


Figure 4. On-Resistance vs Gate to Source Voltage

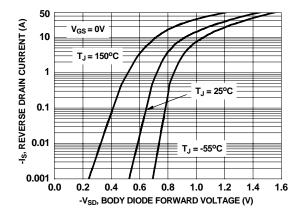


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

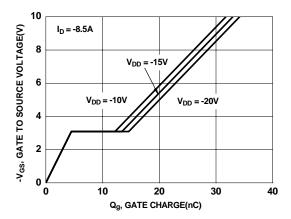


Figure 7. Gate Charge Characteristics

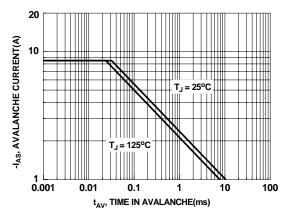


Figure 9. Unclamped Inductive Switching Capability

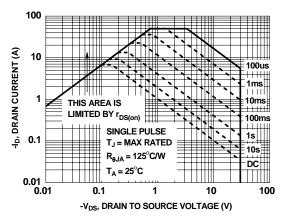


Figure 11. Forward Bias Safe Operating Area

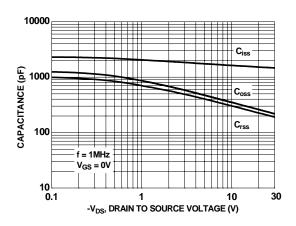


Figure 8. Capacitance vs Drain to Source Voltage

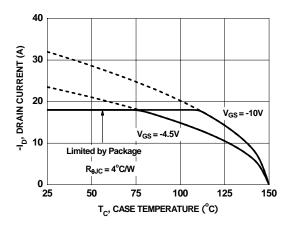


Figure 10. Maximum Continuous Drain Current vs Case Temperature

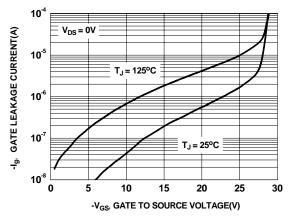


Figure 12. Igss vs Vgss

Typical Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise noted

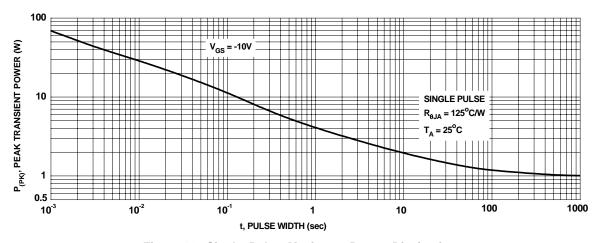


Figure 13. Single Pulse Maximum Power Dissipation

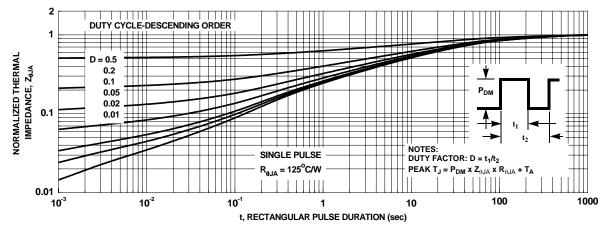
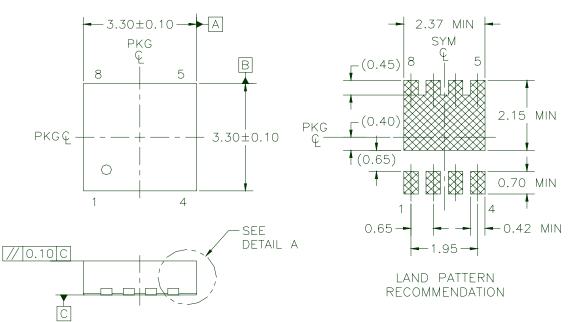
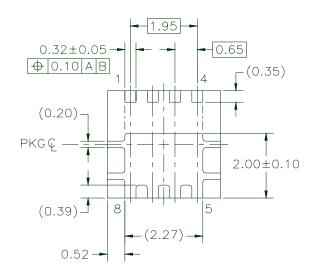
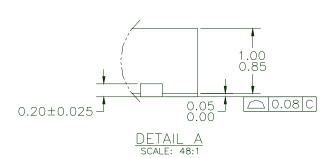


Figure 14. Transient Thermal Response Curve

Dimensional Outline and Pad Layout







PQFN08BREV1

NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE: JEDEC MO229, ISSUE B, VEEC, DATED NOVEMBER 2001.
- ALL DIMENSIONS ARE IN MILLIMETERS.
 DIMENSIONS DO NOT INCLUDE BURRS
 OR MOLD FLASH.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™

CTL™ Current Transfer Logic™ **EcoSPARK**® EfficentMax™ EZSWITCH™ *

Fairchild[®] Fairchild Semiconductor® FACT Quiet Series™

FACT[®] FAST[®] FastvCore™ FlashWriter®* FPS™ F-PFS™ FRFET®

Global Power ResourceSM

Green FPS™

Green FPS™ e-Series™

GTO™ IntelliMAX™ ISOPLANAR™ MegaBuck™ MICROCOUPLER™ MicroFET™

MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ $\mathsf{OPTOLOGIC}^{\mathbb{B}}$ OPTOPLANAR® PDP SPM™ Power-SPM™ PowerTrench®

Programmable Active Droop™

QFET^o $\mathsf{Q}\mathsf{S}^{\mathsf{TM}}$

Quiet Series™ RapidConfigure™

Saving our world, 1mW at a time™

SmartMax™ SMART START™

SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™ SYSTEM ® GENERAL

The Power Franchise®

franchise TinyBoost™ TinyBuck™ TinyLogic[®] TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ μSerDes™

_wer

UHC[®]

Ultra FRFET™ UniFET™ VCX^{TM} VisualMax™

* EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN: NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- 1. Life support devices or systems are devices or systems 2. A critical component in any component of a life support, which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification Product Status		Definition
Advance Information	Formative / In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	This datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 134